Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/615,955	ONO ET AL.	
Examiner	Art Unit	
John D. Lee	2874	

SEARCHED					
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Class	Subclass	Date	Examiner		
250	396R,400, 396ML	4/27/2005	. JDL		
250	397-399	4/27/2005	JDL		
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INT	INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH		)
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JSPTO "WEST" Database searched; search strategy on separate sheet.	4/27/2005	JDL
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